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 [Print Format](#)**1 CHISEL programming operation of scaled NOR flash EEPROMs-effect of voltage scaling, device scaling and technological parameters***Mohapatra, N.R.; Nair, D.R.; Mahapatra, S.; Ramgopal Rao, V.; Shukuri, S.; Bude, J.D.;*Electron Devices, IEEE Transactions on, Volume: 50 Issue: 10   

Page(s): 2104 -2111

[\[Abstract\]](#) [\[PDF Full-Text \(554 KB\)\]](#) **IEEE JNL**